A.3 Machine Model and the Impact on Manufacturing

Workshop Moderator: Charles McClain, Micron Technology, Inc.

The goal of this workshop is to have a dialogue on the need to verify charged conductors and the potential effects on ESDS items in EPAs. Often referred to as machine model (MM) we will be discussing the differences between MM (from a device reliability standpoint) and what is seen on the factory floor when charged conductors influence ESD stability in all processes requiring ESD control. This could be in production or laboratory settings.

This workshop is aimed at generating discussion between factory control and device test, why MM was removed from the design qualification requirements, and what that means inside the EPA.

Please bring your experiences and expertise to this exciting cooperative workshop.